

**INFORMATION DISCLOSURE
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ATTY. DOCKET NO.
071971-0557SERIAL NO.
10/576,518APPLICANT
Tohru YAMAOKA, et al.FILING DATE
April 20, 2006GROUP
2615**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
/B.E./	US	5,490,220	02-06-1996	LOEPPERT	Corresponds w/ JP 7-50899
	US				

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
/B.E./		WO 99/65277	12-16-1999	MICROTRONIC A/S	Corresponds w/ JP 2002-518913	X
/B.E./		JP 2002-518913	06-25-2002		Corresponds w/ WO 99/65277	X
/B.E./		JP 7-50899	02-21-1995	MONOLITHIC SENSORS INC	Corresponds w/ US 5,490,220	JAPAN (w/English Abstract)

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
/B.E./		Japanese Office Action, with English translation, issued in Japanese Patent Application JP 2005-515593, mailed March 11, 2008.	

/Brian Ensey/ EXAMINER

09/09/2008

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.

Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.